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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	291
Number of Logic Elements/Cells	2910
Total RAM Bits	59904
Number of I/O	65
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c3t100c7n

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Section I–2 Altera Corporation

Table 1–1. Cyclone Device Features (Part 2 of 2)									
Feature	EP1C3	EP1C4	EP1C6	EP1C12	EP1C20				
Total RAM bits	59,904	78,336	92,160	239,616	294,912				
PLLs	1	2	2	2	2				
Maximum user I/O pins (1)	104	301	185	249	301				

Note to Table 1–1:

(1) This parameter includes global clock pins.

Cyclone devices are available in quad flat pack (QFP) and space-saving FineLine[®] BGA packages (see Tables 1–2 through 1–3).

Table 1-2. (Table 1–2. Cyclone Package Options and I/O Pin Counts										
Device	100-Pin TQFP (1)	144-Pin TQFP (1), (2)	240-Pin PQFP (1)								
EP1C3	65	104	_	_	_	_					
EP1C4	_	_	_	— 249		301					
EP1C6	_	98	185	185	_	_					
EP1C12	_	_	173	185	249	_					
EP1C20	_	_	_	_	233	301					

Notes to Table 1–2:

- (1) TQFP: thin quad flat pack. PQFP: plastic quad flat pack.
- (2) Cyclone devices support vertical migration within the same package (i.e., designers can migrate between the EP1C3 device in the 144-pin TQFP package and the EP1C6 device in the same package).

Vertical migration means you can migrate a design from one device to another that has the same dedicated pins, JTAG pins, and power pins, and are subsets or supersets for a given package across device densities. The largest density in any package has the highest number of power pins; you must use the layout for the largest planned density in a package to provide the necessary power pins for migration.

For I/O pin migration across densities, cross-reference the available I/O pins using the device pin-outs for all planned densities of a given package type to identify which I/O pins can be migrated. The Quartus® II software can automatically cross-reference and place all pins for you when given a device migration list. If one device has power or ground pins, but these same pins are user I/O on a different device that is in the migration path,the Quartus II software ensures the pins are not used as user I/O in the Quartus II software. Ensure that these pins are connected

to the appropriate plane on the board. The Quartus II software reserves I/O pins as power pins as necessary for layout with the larger densities in the same package having more power pins.

Table 1–3. Cyclone QFP and FineLine BGA Package Sizes									
Dimension	324-Pin FineLine BGA	400-Pin FineLine BGA							
Pitch (mm)	0.5	0.5	0.5	1.0	1.0	1.0			
Area (mm²)	256	484	1,024	289	361	441			
$\begin{array}{c} \text{Length} \times \text{width} \\ \text{(mm} \times \text{mm)} \end{array}$	16×16	22×22	34.6×34.6	17×17	19×19	21×21			

Document Revision History

Table 1–4 shows the revision history for this document.

Table 1-4. Docu	Table 1–4. Document Revision History								
Date and Document Version	Changes Made	Summary of Changes							
May 2008 v1.5	Minor textual and style changes.	_							
January 2007 v1.4	Added document revision history.	_							
August 2005 v1.3	Minor updates.	_							
October 2003 v1.2	Added 64-bit PCI support information.	_							
September 2003 v1.1	 Updated LVDS data rates to 640 Mbps from 311 Mbps. Updated RSDS feature information. 	_							
May 2003 v1.0	Added document to Cyclone Device Handbook.	_							

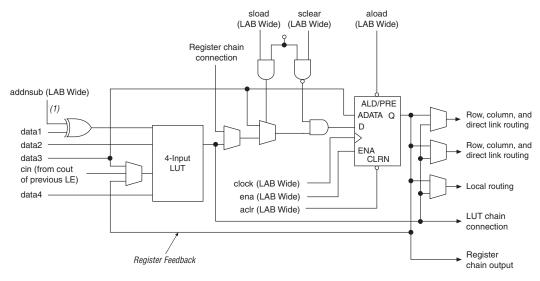
preset/load, synchronous clear, synchronous load, and clock enable control for the register. These LAB-wide signals are available in all LE modes. The addnsub control signal is allowed in arithmetic mode.

The Quartus II software, in conjunction with parameterized functions such as library of parameterized modules (LPM) functions, automatically chooses the appropriate mode for common functions such as counters, adders, subtractors, and arithmetic functions. If required, you can also create special-purpose functions that specify which LE operating mode to use for optimal performance.

Normal Mode

The normal mode is suitable for general logic applications and combinatorial functions. In normal mode, four data inputs from the LAB local interconnect are inputs to a four-input LUT (see Figure 2–6). The Quartus II Compiler automatically selects the carry-in or the data3 signal as one of the inputs to the LUT. Each LE can use LUT chain connections to drive its combinatorial output directly to the next LE in the LAB. Asynchronous load data for the register comes from the data3 input of the LE. LEs in normal mode support packed registers.

Figure 2-6. LE in Normal Mode



Note to Figure 2–6:

This signal is only allowed in normal mode if the LE is at the end of an adder/subtractor chain.

The Quartus II Compiler automatically creates carry chain logic during design processing, or you can create it manually during design entry. Parameterized functions such as LPM functions automatically take advantage of carry chains for the appropriate functions.

The Quartus II Compiler creates carry chains longer than 10 LEs by linking LABs together automatically. For enhanced fitting, a long carry chain runs vertically allowing fast horizontal connections to M4K memory blocks. A carry chain can continue as far as a full column.

Clear and Preset Logic Control

LAB-wide signals control the logic for the register's clear and preset signals. The LE directly supports an asynchronous clear and preset function. The register preset is achieved through the asynchronous load of a logic high. The direct asynchronous preset does not require a NOT-gate push-back technique. Cyclone devices support simultaneous preset/ asynchronous load and clear signals. An asynchronous clear signal takes precedence if both signals are asserted simultaneously. Each LAB supports up to two clears and one preset signal.

In addition to the clear and preset ports, Cyclone devices provide a chip-wide reset pin (DEV_CLRn) that resets all registers in the device. An option set before compilation in the Quartus II software controls this pin. This chip-wide reset overrides all other control signals.

MultiTrack Interconnect

In the Cyclone architecture, connections between LEs, M4K memory blocks, and device I/O pins are provided by the MultiTrack interconnect structure with DirectDriveTM technology. The MultiTrack interconnect consists of continuous, performance-optimized routing lines of different speeds used for inter- and intra-design block connectivity. The Quartus II Compiler automatically places critical design paths on faster interconnects to improve design performance.

DirectDrive technology is a deterministic routing technology that ensures identical routing resource usage for any function regardless of placement within the device. The MultiTrack interconnect and DirectDrive technology simplify the integration stage of block-based designing by eliminating the re-optimization cycles that typically follow design changes and additions.

The MultiTrack interconnect consists of row and column interconnects that span fixed distances. A routing structure with fixed length resources for all devices allows predictable and repeatable performance when

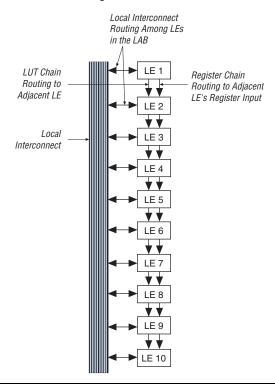


Figure 2–10. LUT Chain and Register Chain Interconnects

The C4 interconnects span four LABs or M4K blocks up or down from a source LAB. Every LAB has its own set of C4 interconnects to drive either up or down. Figure 2–11 shows the C4 interconnect connections from a LAB in a column. The C4 interconnects can drive and be driven by all types of architecture blocks, including PLLs, M4K memory blocks, and column and row IOEs. For LAB interconnection, a primary LAB or its LAB neighbor can drive a given C4 interconnect. C4 interconnects can drive each other to extend their range as well as drive row interconnects for column-to-column connections.

Independent Clock Mode

The M4K memory blocks implement independent clock mode for true dual-port memory. In this mode, a separate clock is available for each port (ports A and B). Clock A controls all registers on the port A side, while clock B controls all registers on the port B side. Each port, A and B, also supports independent clock enables and asynchronous clear signals for port A and B registers. Figure 2–17 shows an M4K memory block in independent clock mode.

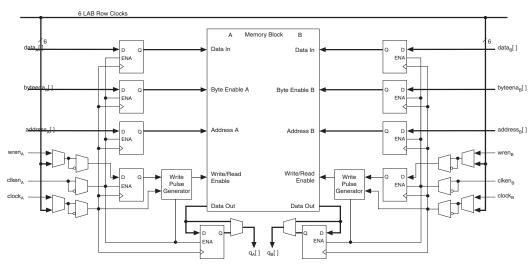


Figure 2–17. Independent Clock Mode Notes (1), (2)

Notes to Figure 2–17:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Input/Output Clock Mode

Input/output clock mode can be implemented for both the true and simple dual-port memory modes. On each of the two ports, A or B, one clock controls all registers for inputs into the memory block: data input, wren, and address. The other clock controls the block's data output registers. Each memory block port, A or B, also supports independent clock enables and asynchronous clear signals for input and output registers. Figures 2–18 and 2–19 show the memory block in input/output clock mode.

Read/Write Clock Mode

The M4K memory blocks implement read/write clock mode for simple dual-port memory. You can use up to two clocks in this mode. The write clock controls the block's data inputs, wraddress, and wren. The read clock controls the data output, rdaddress, and rden. The memory blocks support independent clock enables for each clock and asynchronous clear signals for the read- and write-side registers. Figure 2–20 shows a memory block in read/write clock mode.

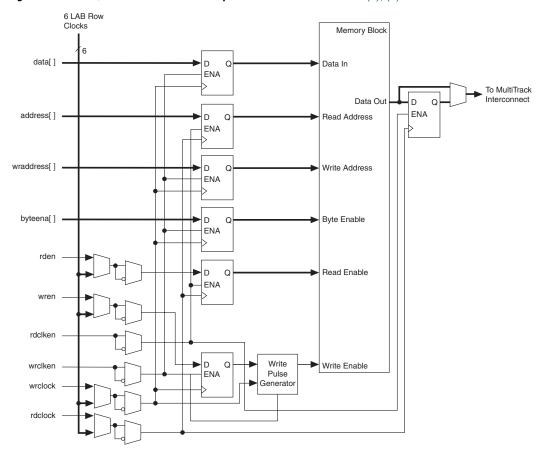


Figure 2–20. Read/Write Clock Mode in Simple Dual-Port Mode Notes (1), (2)

Notes to Figure 2–20:

- (1) All registers shown except the rden register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Advanced I/O Standard Support

Cyclone device IOEs support the following I/O standards:

- 3.3-V LVTTL/LVCMOS
- 2.5-V LVTTL/LVCMOS
- 1.8-V LVTTL/LVCMOS
- 1.5-V LVCMOS
- 3.3-V PCI
- LVDS
- RSDS
- SSTL-2 class I and II
- SSTL-3 class I and II
- Differential SSTL-2 class II (on output clocks only)

Table 2–12 describes the I/O standards supported by Cyclone devices.

Table 2–12. Cyclone I/O Standards									
I/O Standard	Туре	Input Reference Voltage (V _{REF}) (V)	Output Supply Voltage (V _{CCIO}) (V)	Board Termination Voltage (V _{TT}) (V)					
3.3-V LVTTL/LVCMOS	Single-ended	N/A	3.3	N/A					
2.5-V LVTTL/LVCMOS	Single-ended	N/A	2.5	N/A					
1.8-V LVTTL/LVCMOS	Single-ended	N/A	1.8	N/A					
1.5-V LVCMOS	Single-ended	N/A	1.5	N/A					
3.3-V PCI (1)	Single-ended	N/A	3.3	N/A					
LVDS (2)	Differential	N/A	2.5	N/A					
RSDS (2)	Differential	N/A	2.5	N/A					
SSTL-2 class I and II	Voltage-referenced	1.25	2.5	1.25					
SSTL-3 class I and II	Voltage-referenced	1.5	3.3	1.5					
Differential SSTL-2 (3)	Differential	1.25	2.5	1.25					

Notes to Table 2-12:

- (1) There is no megafunction support for EP1C3 devices for the PCI compiler. However, EP1C3 devices support PCI by using the LVTTL 16-mA I/O standard and drive strength assignments in the Quartus II software. The device requires an external diode for PCI compliance.
- (2) EP1C3 devices in the 100-pin TQFP package do not support the LVDS and RSDS I/O standards.
- (3) This I/O standard is only available on output clock pins (PLL_OUT pins). EP1C3 devices in the 100-pin package do not support this I/O standard as it does not have PLL_OUT pins.

Cyclone devices contain four I/O banks, as shown in Figure 2–35. I/O banks 1 and 3 support all the I/O standards listed in Table 2–12. I/O banks 2 and 4 support all the I/O standards listed in Table 2–12 except the 3.3-V PCI standard. I/O banks 2 and 4 contain dual-purpose DQS, DQ,



Cyclone devices must be within the first 8 devices in a JTAG chain. All of these devices have the same JTAG controller. If any of the Cyclone devices are in the 9th or after they will fail configuration. This does not affect the SignalTap® II logic analyzer.



For more information on JTAG, refer to the following documents:

- AN 39: IEEE Std. 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices
- Jam Programming & Test Language Specification

SignalTap II Embedded Logic Analyzer

Cyclone devices feature the SignalTap II embedded logic analyzer, which monitors design operation over a period of time through the IEEE Std. 1149.1 (JTAG) circuitry. A designer can analyze internal logic at speed without bringing internal signals to the I/O pins. This feature is particularly important for advanced packages, such as FineLine BGA packages, because it can be difficult to add a connection to a pin during the debugging process after a board is designed and manufactured.

Configuration

The logic, circuitry, and interconnects in the Cyclone architecture are configured with CMOS SRAM elements. Altera FPGAs are reconfigurable and every device is tested with a high coverage production test program so the designer does not have to perform fault testing and can instead focus on simulation and design verification.

Cyclone devices are configured at system power-up with data stored in an Altera configuration device or provided by a system controller. The Cyclone device's optimized interface allows the device to act as controller in an active serial configuration scheme with the new low-cost serial configuration device. Cyclone devices can be configured in under 120 ms using serial data at 20 MHz. The serial configuration device can be programmed via the ByteBlaster II download cable, the Altera Programming Unit (APU), or third-party programmers.

In addition to the new low-cost serial configuration device, Altera offers in-system programmability (ISP)-capable configuration devices that can configure Cyclone devices via a serial data stream. The interface also enables microprocessors to treat Cyclone devices as memory and configure them by writing to a virtual memory location, making reconfiguration easy. After a Cyclone device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Real-time changes can be made during system operation, enabling innovative reconfigurable computing applications.

Table 4-2. C	Table 4–2. Cyclone Device Recommended Operating Conditions (Part 2 of 2)									
Symbol	Parameter	Conditions	Minimum	Maximum	Unit					
Vo	Output voltage		0	V _{CCIO}	V					
T _J	Operating junction temperature	For commercial use	0	85	° C					
		For industrial use	-40	100	° C					
		For extended- temperature use	-40	125	° C					

Table 4-	Table 4–3. Cyclone Device DC Operating Conditions Note (6)									
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit				
I _I	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V (8)	-10	_	10	μΑ				
I _{OZ}	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V (8)	-10	_	10	μА				
I _{CC0}	V _{CC} supply current (standby)	EP1C3	_	4	_	mA				
	(All M4K blocks in power-down mode) (7)	EP1C4	_	6	_	mA				
		EP1C6	_	6	_	mA				
		EP1C12	_	8	_	mA				
		EP1C20	_	12	_	mA				
R _{CONF} (9)		$V_{I} = 0 \text{ V}; V_{CCI0} = 3.3 \text{ V}$	15	25	50	kΩ				
	before and during configuration	$V_{I} = 0 \text{ V}; V_{CCI0} = 2.5 \text{ V}$	20	45	70	kΩ				
		$V_I = 0 \ V; \ V_{CCI0} = 1.8 \ V$	30	65	100	kΩ				
		$V_I = 0 \ V; \ V_{CCI0} = 1.5 \ V$	50	100	150	kΩ				
	Recommended value of I/O pin external pull-down resistor before and during configuration	_	_	1	2	kΩ				

Table 4-4.	Table 4–4. LVTTL Specifications									
Symbol	Parameter	Conditions	Minimum	Maximum	Unit					
V _{CCIO}	Output supply voltage	_	3.0	3.6	V					
V _{IH}	High-level input voltage	_	1.7	4.1	V					
V _{IL}	Low-level input voltage	_	-0.5	0.7	V					
V _{OH}	High-level output voltage	$I_{OH} = -4 \text{ to } -24 \text{ mA } (11)$	2.4	_	V					
V _{OL}	Low-level output voltage	I _{OL} = 4 to 24 mA (11)	_	0.45	V					

Table 4–13	Table 4–13. SSTL-3 Class I Specifications (Part 2 of 2)									
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit				
V_{REF}	Reference voltage	_	1.3	1.5	1.7	V				
V _{IH}	High-level input voltage	_	V _{REF} + 0.2	_	V _{CCIO} + 0.3	٧				
V_{IL}	Low-level input voltage	_	-0.3	_	V _{REF} - 0.2	٧				
V _{OH}	High-level output voltage	$I_{OH} = -8 \text{ mA } (11)$	V _{TT} + 0.6	_	_	V				
V _{OL}	Low-level output voltage	I _{OL} = 8 mA (11)	_	_	V _{TT} - 0.6	٧				

Table 4–14	Table 4–14. SSTL-3 Class II Specifications									
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit				
V _{CCIO}	Output supply voltage	_	3.0	3.3	3.6	V				
V _{TT}	Termination voltage	_	V _{REF} - 0.05	V _{REF}	V _{REF} + 0.05	V				
V _{REF}	Reference voltage	_	1.3	1.5	1.7	V				
V _{IH}	High-level input voltage	_	V _{REF} + 0.2	_	V _{CCIO} + 0.3	V				
V _{IL}	Low-level input voltage	_	-0.3	_	V _{REF} - 0.2	V				
V _{OH}	High-level output voltage	I _{OH} = -16 mA (11)	V _{TT} + 0.8	_	_	V				
V _{OL}	Low-level output voltage	I _{OL} = 16 mA (11)	_	_	V _{TT} – 0.8	V				

Table 4–15. Bus Hold Parameters										
			V _{CCIO} Level							
Parameter	Conditions	1.5	5 V	1.8	B V	2.	5 V	3.3	3 V	Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	$V_{IN} > V_{IL}$ (maximum)	_	_	30	_	50	_	70	_	μΑ
High sustaining current	V _{IN} < V _{IH} (minimum)	_	_	-30	_	-50	_	-70	_	μΑ
Low overdrive current	0 V < V _{IN} < V _{CCIO}	_	_	_	200	_	300	_	500	μА
High overdrive current	0 V < V _{IN} < V _{CCIO}	_	_	_	-200	_	-300	_	-500	μА

Performance

The maximum internal logic array clock tree frequency is limited to the specifications shown in Table 4–19.

Table 4–19. Clock Tree Maximum Performance Specification											
Parameter	Definition	-6 Speed Grade		-7 Speed Grade			-8 Speed Grade			Units	
Parameter		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIIS
Clock tree f _{MAX}	Maximum frequency that the clock tree can support for clocking registered logic		_	405	_	_	320		_	275	MHz

Table 4–20 shows the Cyclone device performance for some common designs. All performance values were obtained with the Quartus II software compilation of library of parameterized modules (LPM) functions or megafunctions. These performance values are based on EP1C6 devices in 144-pin TQFP packages.

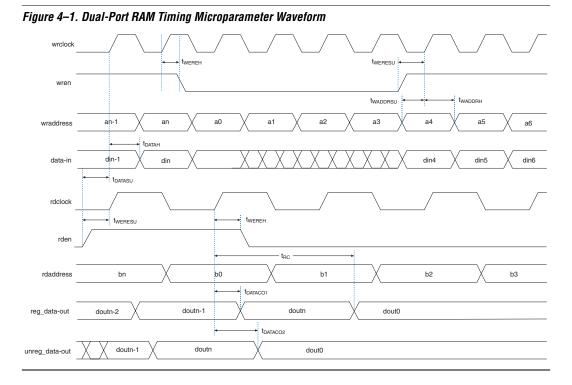
Table 4–20. Cyclone Device Performance								
			R	esources U	sed	Performance		
Resource Used	Design Size and Function	Mode	LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)
LE	16-to-1 multiplexer	_	21	_	_	405.00	320.00	275.00
	32-to-1 multiplexer	_	44	_	_	317.36	284.98	260.15
	16-bit counter	_	16	_	_	405.00	320.00	275.00
	64-bit counter (1)	_	66	_	_	208.99	181.98	160.75

Table 4–22. IOE Internal Timing Microparameter Descriptions					
Symbol	Parameter				
t_{SU}	IOE input and output register setup time before clock				
t _H	IOE input and output register hold time after clock				
t _{CO}	IOE input and output register clock-to-output delay				
t _{PIN2COMBOUT_R}	Row input pin to IOE combinatorial output				
t _{PIN2COMBOUT_C}	Column input pin to IOE combinatorial output				
t _{COMBIN2PIN_R}	Row IOE data input to combinatorial output pin				
t _{COMBIN2PIN_C}	Column IOE data input to combinatorial output pin				
t _{CLR}	Minimum clear pulse width				
t _{PRE}	Minimum preset pulse width				
t _{CLKHL}	Minimum clock high or low time				

Table 4–23. M4K Block Internal Timing Microparameter Descriptions					
Symbol	Parameter				
t _{M4KRC}	Synchronous read cycle time				
t _{M4KWC}	Synchronous write cycle time				
t _{M4KWERESU}	Write or read enable setup time before clock				
t _{M4KWEREH}	Write or read enable hold time after clock				
t _{M4KBESU}	Byte enable setup time before clock				
t _{M4KBEH}	Byte enable hold time after clock				
t _{M4KDATAASU}	A port data setup time before clock				
t _{M4KDATAAH}	A port data hold time after clock				
t _{M4KADDRASU}	A port address setup time before clock				
t _{M4KADDRAH}	A port address hold time after clock				
t _{M4KDATABSU}	B port data setup time before clock				
t _{M4KDATABH}	B port data hold time after clock				
t _{M4KADDRBSU}	B port address setup time before clock				
t _{M4KADDRBH}	B port address hold time after clock				
t _{M4KDATACO1}	Clock-to-output delay when using output registers				
t _{M4KDATACO2}	Clock-to-output delay without output registers				
t _{M4KCLKHL}	Minimum clock high or low time				
t _{M4KCLR}	Minimum clear pulse width				

Table 4–24. Routing Delay Internal Timing Microparameter Descriptions					
Symbol Parameter					
t _{R4}	Delay for an R4 line with average loading; covers a distance of four LAB columns				
t _{C4}	Delay for an C4 line with average loading; covers a distance of four LAB rows				
t _{LOCAL}	Local interconnect delay				

Figure 4–1 shows the memory waveforms for the M4K timing parameters shown in Table 4–23.



Internal timing parameters are specified on a speed grade basis independent of device density. Tables 4–25 through 4–28 show the internal timing microparameters for LEs, IOEs, TriMatrix memory structures, DSP blocks, and MultiTrack interconnects.

Table 4–25. LE In	Table 4–25. LE Internal Timing Microparameters							
	-6		-	7	-8		11-14	
Symbol	Min	Max	Min	Max	Min	Max	Unit	
t _{SU}	29	_	33	_	37	_	ps	
t _H	12	_	13	_	15	_	ps	
t _{CO}	_	173	_	198	_	224	ps	
t _{LUT}	_	454	_	522	_	590	ps	
t _{CLR}	129	_	148	_	167	_	ps	
t _{PRE}	129	_	148	_	167	_	ps	
t _{CLKHL}	1,234	_	1,562	_	1,818		ps	

Table 4–26. IOE Internal Timing Microparameters							
Cumbal	-6		-	7	-	11:4	
Symbol	Min	Max	Min	Max	Min	Max	Unit
t _{SU}	348	_	400	_	452	_	ps
t _H	0	_	0	_	0	_	ps
t _{CO}	_	511	_	587	_	664	ps
t _{PIN2COMBOUT_R}	_	1,130	_	1,299	_	1,469	ps
t _{PIN2COMBOUT_C}	_	1,135	_	1,305	_	1,475	ps
t _{COMBIN2PIN_R}	_	2,627	_	3,021	_	3,415	ps
t _{COMBIN2PIN_C}	_	2,615	_	3,007	_	3,399	ps
t _{CLR}	280	_	322	_	364	_	ps
t _{PRE}	280	_	322	_	364	_	ps
t _{CLKHL}	1,234	_	1,562	_	1,818	_	ps

Cumbal	-	-6		7	-8		
Symbol	Min	Max	Min	Max	Min	Max	Unit
t _{M4KRC}	_	4,379		5,035		5,691	ps
t _{M4KWC}	_	2,910		3,346		3,783	ps
t _{M4KWERESU}	72	_	82	_	93	_	ps
t _{M4KWEREH}	43	_	49	_	55	_	ps
t _{M4KBESU}	72	_	82	_	93	_	ps
t _{M4KBEH}	43	_	49	_	55	_	ps
t _{M4KDATAASU}	72	_	82	_	93	_	ps
t _{M4KDATAAH}	43	_	49	_	55	_	ps
t _{M4KADDRASU}	72	_	82	_	93	_	ps
t _{M4KADDRAH}	43	_	49	_	55	_	ps
t _{M4KDATABSU}	72	_	82	_	93	_	ps
t _{M4KDATABH}	43	_	49	_	55	_	ps
t _{M4KADDRBSU}	72	_	82	_	93	_	ps
t _{M4KADDRBH}	43	_	49	_	55	_	ps
t _{M4KDATACO1}	_	621	_	714	_	807	ps
t _{M4KDATACO2}	_	4,351	_	5,003	_	5,656	ps
t _{M4KCLKHL}	1,234	_	1,562	_	1,818	_	ps
t _{M4KCLR}	286	_	328		371		ps

Table 4–28. Routing Delay Internal Timing Microparameters							
Cumbal	-	-6		-7		-8	
Symbol	Min	Max	Min	Max	Min	Max	Unit
t _{R4}	_	261	_	300	_	339	ps
t _{C4}	_	338	_	388	_	439	ps
t _{LOCAL}	_	244	_	281	_	318	ps

External Timing Parameters

External timing parameters are specified by device density and speed grade. Figure 4–2 shows the timing model for bidirectional IOE pin timing. All registers are within the IOE.

July 2003 v1.1	Updated timing information. Timing finalized for EP1C6 and EP1C20 devices. Updated performance information. Added PLL Timing section.	_
May 2003 v1.0	Added document to Cyclone Device Handbook.	_

February 2005 v1.1	Updated Figure 5-1.	_
May 2003 v1.0	Added document to Cyclone Device Handbook.	_